

# IPC313N10N3R

### **OptiMOS<sup>™</sup>3** Power MOS Transistor Chip

Туре	V <sub>(BR)DSS</sub>	<b>R</b> <sub>DS(on)</sub>	Die size	Thickness
IPC313N10N3R	100 V	$2.7 \text{ m}\Omega^{1)}$	6 * 5.2 mm <sup>2</sup>	220 µm

### DESCRIPTION

- N-channel enhancement mode
- For dynamic characterization refer to the datasheet of IPB027N10N3 G<sup>2)</sup>
- AQL 0.65 for visual inspection according to failure catalogue
- Electrostatic Discharge Sensitive Device according to JEDEC
- Die bond: soldered or glued
- Backside metallization: NiV system
- Frontside metallization: AICu system
- Passivation: nitride (only on edge structure)

### Electrical Characteristics on Wafer Level

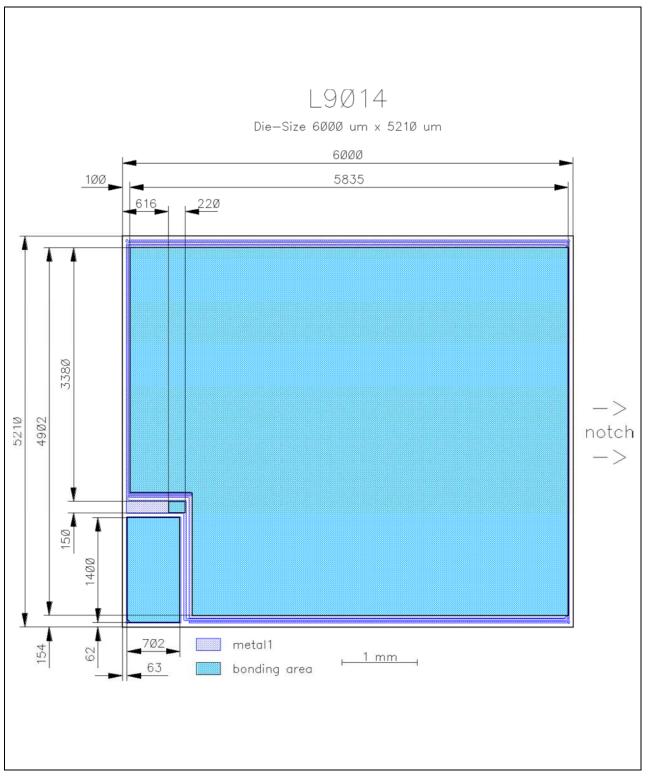
at  $T_j = 25 \circ C$ , unless otherwise specified.

Parameter	Symbol	Value		Unit	Conditions	
		min.	typ.	max.		
Drain-source breakdown voltage	V(BR)DSS	100	-	-	V	$V_{GS} = 0V$
						$I_D = 1 \text{ mA}$
Gate threshold voltage	V <sub>GS(th)</sub>	2	2.7	3.5	V	$V_{DS} = V_{GS}$
						I <sub>D</sub> = 275 μA
Zero gate voltage drain current	I <sub>DSS</sub>	-	0.1	1	μA	$V_{GS} = 0V$
						V <sub>DS</sub> = 100 V
Gate-source leakage current	I <sub>GSS</sub>	-	1	100	nA	$V_{GS} = 20 V$
						$V_{DS} = 0 V$
Drain-source on-resistance	$R_{\rm DS(on)}$	-	1.9 <sup>3)</sup>	100 4)	mΩ	V <sub>GS</sub> = 10 V
						I <sub>D</sub> = 2.0 A
Reverse diode forward on-voltage	Vsd	-	1.0	1.2	V	V <sub>GS</sub> =0 V
						I <sub>F</sub> = 1 A
Internal gate resistance	R <sub>G</sub>	-	8	-	Ω	
Avalanche energy, single pulse	Eas	-	45 <sup>5)</sup>	-	mJ	I <sub>D</sub> = 30 A, <i>R</i> <sub>GS</sub> =25 Ω



IPC313N10N3R

Chip-Layout:



<sup>1)</sup> packaged in a P-TO263-3 (see ref. product)

 $^{\scriptscriptstyle 2)}$  IPB027N10N3 G dynamic characterization does not include the internal added  $R_{\rm G}$ 

 $^{3)}$  typical bare die  $R_{\text{DS(on)}};\,V_{\text{GS}}{=}10V$ 

- <sup>4)</sup> limited by wafer test-equipment
- <sup>5)</sup> Wafer tested. For general avalanche capability refer to the datasheet of IPB027N10N3 G



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